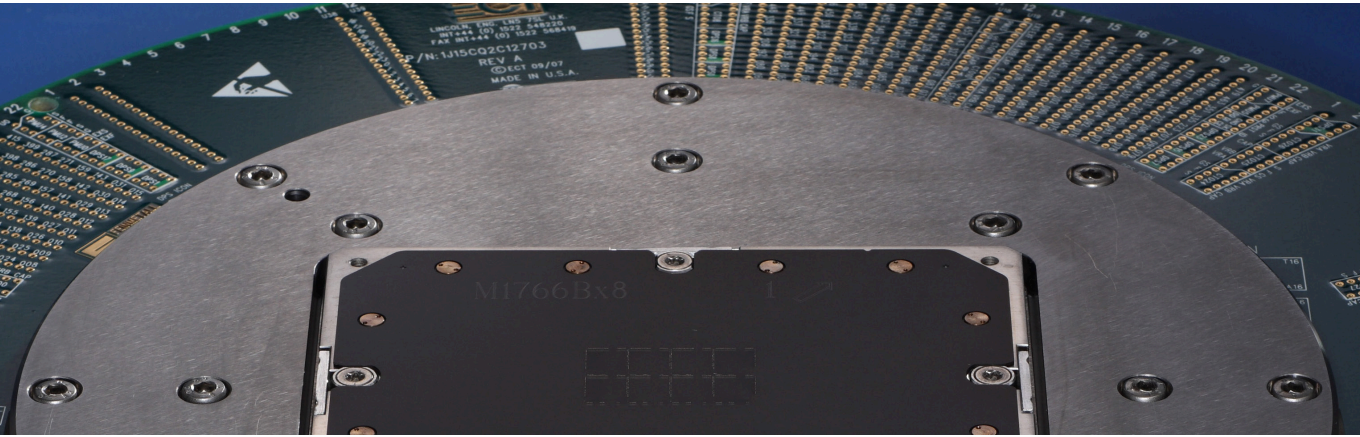


WAFER PROBE CARD SOLUTIONS



Vertical Probe Card ViProbe® and ViProbe®II - *From the Established Solution to the Next Generation*

For years, the FEINMETALL ViProbe® has dominated the vertical probe card industry. Several advantages such as the stable contact performance as well as the simple exchange of the contact elements and outstanding temperature behavior make this probing solution the favorite to the automotive industry.

With the introduction of the next generation of vertical wafer probing, the ViProbe®II, all these advantages are extended by multiple lifetime extension options and further security additions to ensure security of the DUT.

Advantages

- Accurate wafer probing on fine-pitch pads over the whole temperature range
- Simple exchange of single contact elements, complete replacement of the probes and even probe heads by the customer leads to lowest cost-of-ownership
- Adjustable to most applications: from high pin count, to copper probing up to fine-pitch
- Multiple lifetime extension
- Extended security features of the probe head

Specifications at a glance	ViProbe®	ViProbe®II
Min pitch of the DUT	Down to 56 µm	Down to 40 µm
Diameter of the contact element	Down to 1.6 mil	Down to 1.1 mil
Max active area	Up to 80 mm x 80 mm	Up to 105 mm x 105 mm
Capable temperature range	From -55°C to 180°C	From -55°C to 180°C
Current carrying capability at RT	Up to 800 mA	Up to 800 mA
Contact force at rec. OD	From 2.6 cN to 10.8 cN	From 2.2 cN to 10.8 cN